



# SV1C Personalized SerDes Tester



Data Sheet

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# Introduction

## Overview

The SV1C Personalized SerDes Tester is an ultra-portable, high-performance instrument that creates a new category of tool for high-speed digital product engineering teams. It integrates multiple technologies in order to enable the self-contained test and measurement of complex SerDes interfaces such as PCI Express Gen 3, MIPI M-PHY, Thunderbolt, or USB3. Coupled with a seamless, easy-to-use development environment, this tool enables product engineers with widely varying skills to efficiently work with and develop SerDes verification algorithms. The SV1C fits in one hand and contains 8 independent stimulus generation ports, 8 independent capture and measurement ports and various clocking, synchronization and lane-expansion capabilities. It has been designed specifically to address the growing need of a parallel, system-oriented test methodology while offering world-class signal-integrity features such as jitter injection and jitter measurement.

With a small form factor, an extensive signal-integrity feature set, and an exceptionally powerful software development environment, the SV1C is not only suitable for signal-integrity verification engineers that perform traditional characterization tasks, but it is also ideal for FPGA developers and software developers who need rapid turnaround signal verification tools or hardware-software interoperability confirmation tools. The SV1C integrates state of the art functions such as digital data capture, bit error rate measurement, clock recovery, jitter decomposition and jitter generation.

## Key Benefits

- True parallel bit-error-rate measurement across 8 lanes
- Fully-synthesized integrated jitter injection on all lanes
- Fully-automated integrated jitter testing on all lanes
- Optimized pattern generator rise-time for receiver stress test applications
- Flexible pre-emphasis and equalization
- Flexible loopback support per lane
- Hardware clock recovery per lane
- State of the art programming environment based on the highly intuitive Python language
- Integrated device control through SPI, I2C, or JTAG
- Reconfigurable, protocol customization (on request)

# Applications

Parallel PHY validation of serial bus standards such as:

- PCI Express (PCIe)
- UHS-2
- MIPI M-PHY
- CPRI
- USB
- HDMI
- Thunderbolt
- XAUI
- JESD204B
- SATA

Interface test of electrical/optical media such as:

- Backplane
- Cable
- CFP MSA, SFP MSA, SFP+ MSA

Plug-and-play system-level validation such as:

- PCI Express
- DisplayPort sink/source
- MIPI M-PHY

Timing verification:

- PLL transfer function measurement
- Clock recovery bandwidth verification
- Frequency ppm offset characterization

Mixed-technology applications:

- High-speed ADC and DAC (JESD204) data capture and/or synthesis
- FPGA-based system development
- Channel and device emulation

Clock-recovery triggering for external oscilloscope or BERT equipment

# Physical Connectors

Figure 1 shows the high-speed differential transmit and receive data pins, reference clock connectors, power and USB ports on the SV1C chassis. The auxiliary triggers and programmable SCSi ports are optional features.

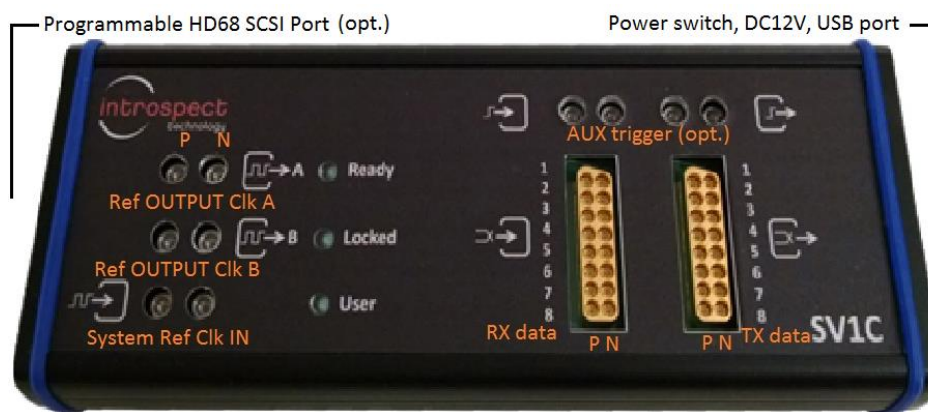


Figure 1 SV1C connectors

## Features

### Multi-Lane Loopback

The SV1C is the only bench-top tool that offers instrument-grade loopback capability on all differential lanes. The loopback capability of the SV1C includes:

- Retiming of data for the purpose of decoupling DUT receiver performance from DUT transmitter performance
- Arbitrary jitter or voltage swing control on loopback data

Figure 2 shows two common loopback configurations that can be used with the SV1C. In the first configuration, a single DUT's transmitter and receiver channels are connected together through the SV1C. In the second configuration, arbitrary pattern testing can be performed on an end-to-end communications link. The SV1C is used to pass data through from a traffic generator (such as an end-point on a real system board) to the DUT while stressing the DUT receiver with jitter, skew, or voltage swing.

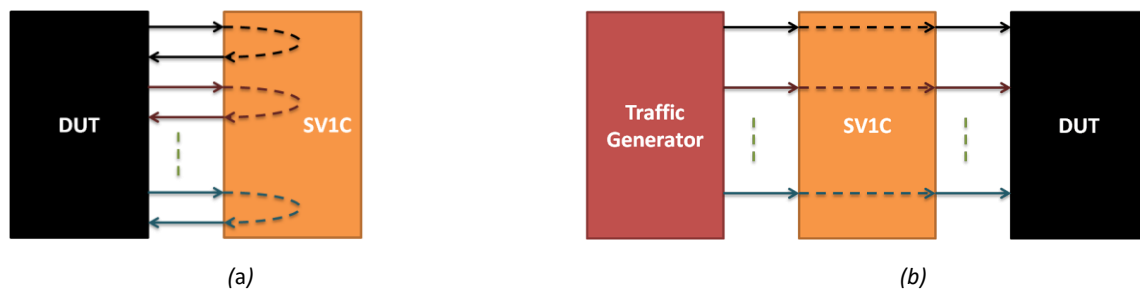


Figure 2 Illustration of loopback applications.

### Multiple-Source Jitter Injection

The SV1C is capable of generating calibrated jitter stress on any data pattern and any output lane configuration. Sinusoidal jitter injection is calibrated in the time and frequency domain in order to generate high-purity stimulus signals as shown in Figure 3.

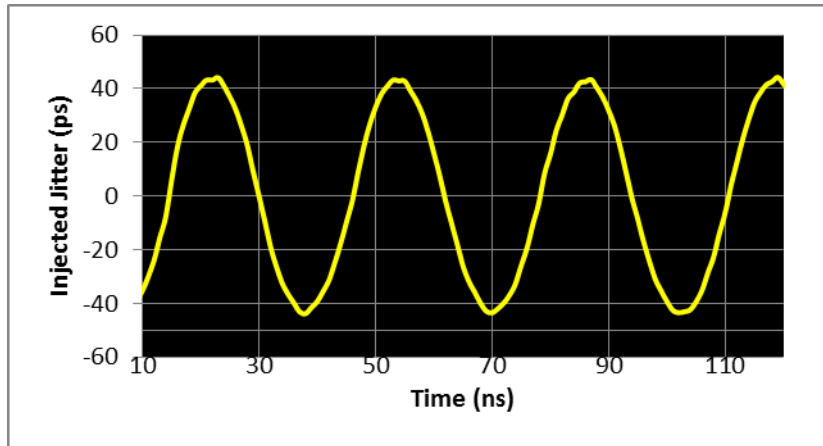


Figure 3 Illustration of calibrated jitter waveform.

The jitter injection feature is typically exploited in order to perform automated jitter tolerance testing as shown in the example in Figure 4. As is the case for other features in the SV1C Personalized SerDes Tester, jitter tolerance testing happens in parallel across all lanes. For advanced applications, the SV1C also includes RJ injection and a third-source arbitrary waveform jitter synthesizer.

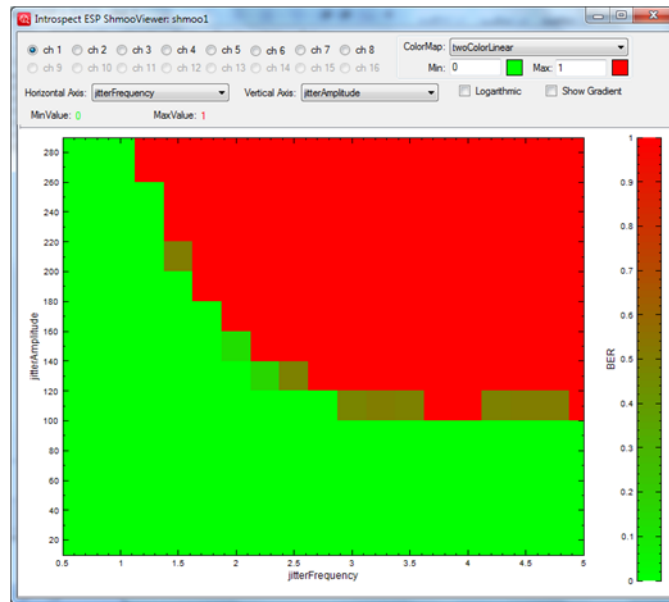


Figure 4 Illustration of jitter tolerance curve.

## Pre-Emphasis Generation

Conventionally offered as a separate instrument, per-lane pre-emphasis control is integrated on the 8-lane SV1C tester. The user can individually set the transmitter pre-emphasis using a built-in Tap structure. Pre-emphasis allows the user to optimize signal characteristics at the DUT input pins.

Each transmitter in the SV1C implements a discrete-time linear equalizer as part of the driver circuit. An illustration of such equalizer is shown in Figure 5, and sample synthesized waveform shapes are shown in Figure 6.

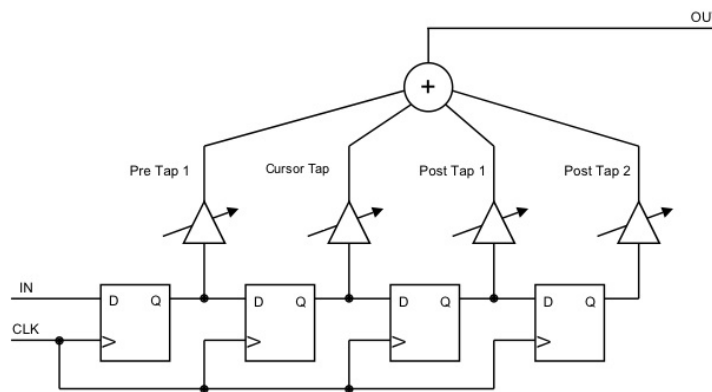


Figure 5 Illustration of pre-emphasis design.

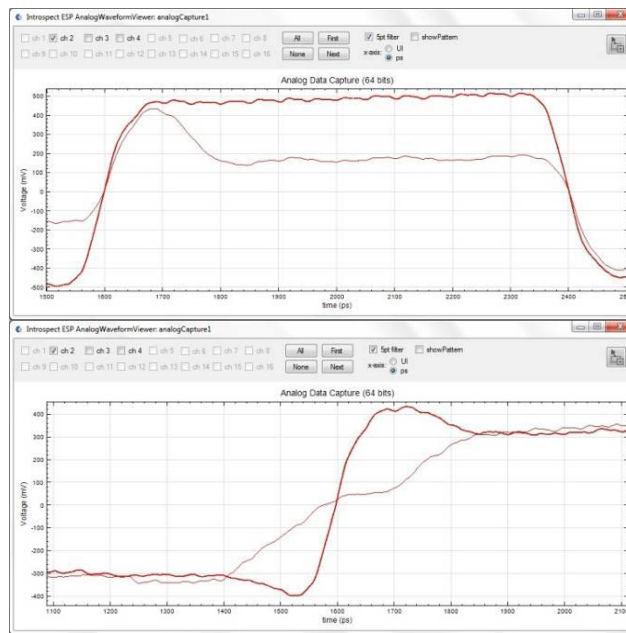


Figure 6 Illustration of multiple waveform shapes that can be synthesized using the pre-emphasis function of the SV1C.



## Programmable SSC Generation and Frequency Synthesis

The SV1C incorporates precision frequency synthesis technology that allows for the generation of programmable SSC waveforms at any data rate. The SSC waveforms are superimposed on the pattern generator outputs, and they coexist with other jitter injection sources of the SV1C. Thus, a truly complete jitter cocktail can be produced for the most thorough receiver validation. Figure 7 illustrates the SSC capability of the SV1C. In the figure, the SV1C is programmed to synthesize four slightly different modulation frequencies showcasing the precision programmability of the tool.

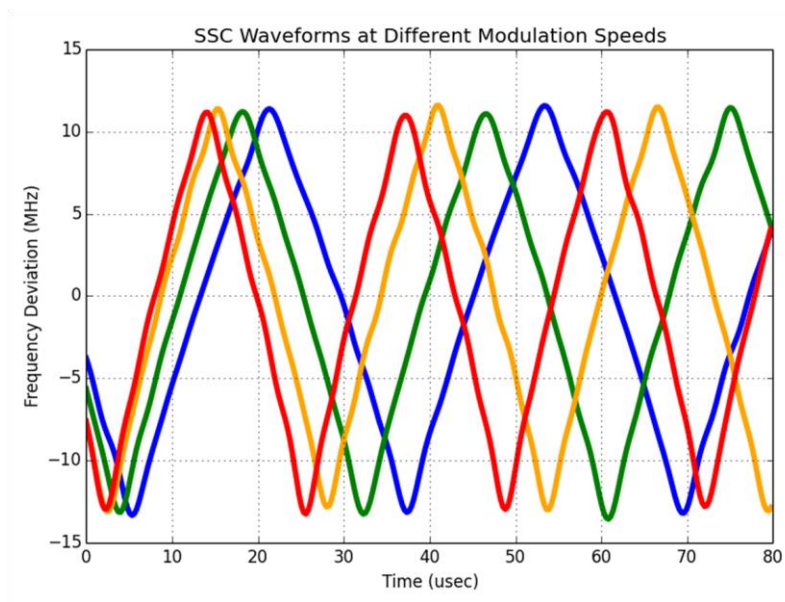


Figure 7 Programmable SSC generation.

## Per-Lane Clock Recovery and Unique Dual-Path Architecture

Like pre-emphasis, conventional tools often require separate clock recovery instrumentation. In the SV1C, each receiver has its own embedded analog clock recovery circuit. Additionally, the clock recovery is monolithically integrated directly inside the receiver's high-speed sampler, thus offering the lowest possible sampling latency in a test and measurement instrument. The user does not have to make special connections or carefully match cable lengths. The monolithic nature of the SV1C clock recovery helps achieve wide tracking bandwidth for measuring signals that possess spread-spectrum clocking or very high amplitude wander. Figure 8 shows a block diagram of the clock recovery capability inside the SV1C Personalized SerDes Tester.

Also shown in Figure 8 is the dual-path receiver architecture of the SV1C. This unique architecture allows the SV1C to operate as both a digital capture/analysis instrument and an analog measurement instrument. A feature rich clock management system allows for customization of the SV1C to specific customer requirements.

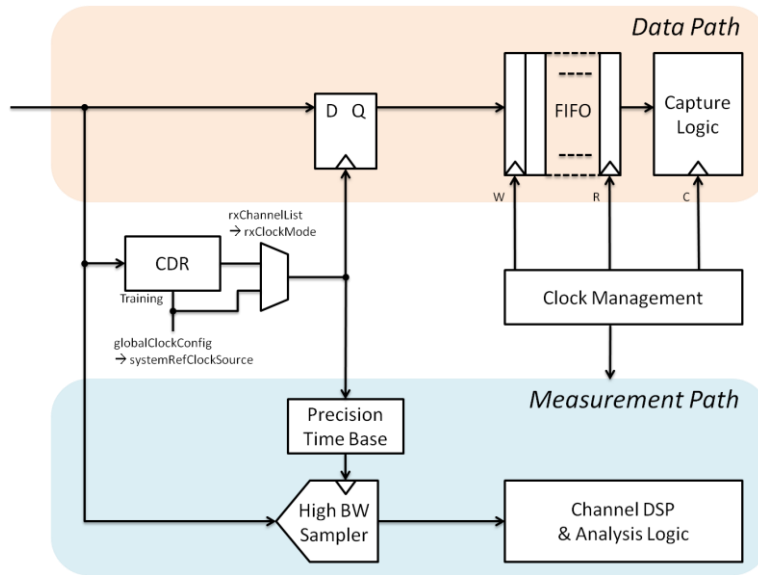


Figure 8 Per-lane clock recovery and dual-path architecture.

## Auxiliary Control Port

The SV1C includes a low-speed auxiliary control port that is based on a standard SCSI connector (Figure 9). This port enables controlling DUT registers through JTAG, I2C, or SPI. Additionally, the port includes reconfigurable trigger and flag capability for synchronizing the SV1C with external tools or events.

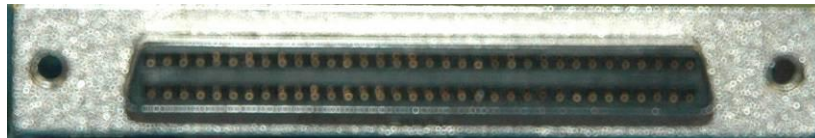


Figure 9 Photograph of the auxiliary control port on the SV1C.

## Analysis

The SV1C instrument has an independent Bit Error Rate Tester (BERT) for each of its input channels. Each BERT compares recovered (retimed) data from a single input channel against a specified data pattern and reports the bit error count.

Apart from error counting, the instrument offers a wide range of measurement and analysis features including:

- Jitter separation
- Eye mask testing
- Voltage level, pre-emphasis level, and signal parameter measurement
- Frequency measurement and SSC profile extraction

Figure 10 illustrates a few of the analysis and reporting features of the SV1C. Starting from the top left and moving in a clock-wise manner, the figure illustrates bathtub acquisition and analysis, waveform capture, raw data viewing, and eye diagram plotting. As always, these analysis options are executed in parallel on all activated lanes.

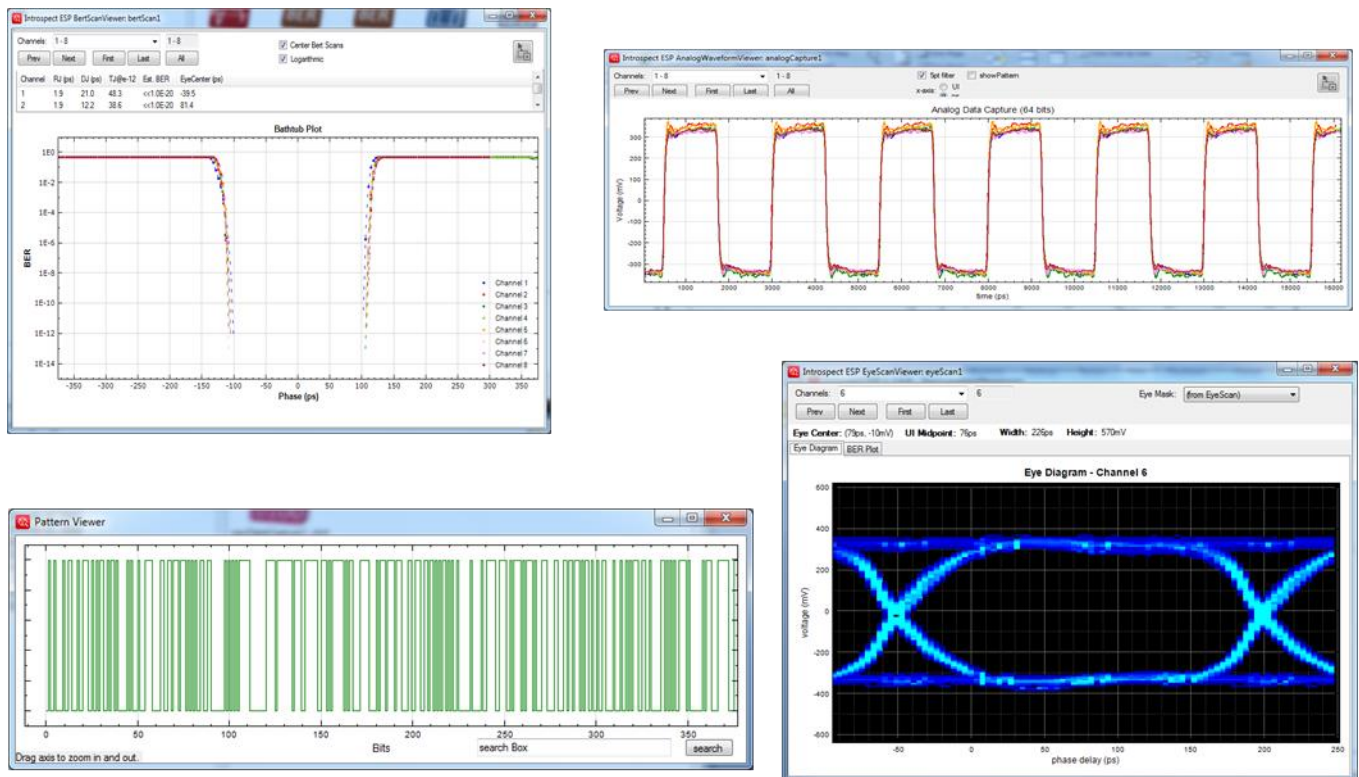
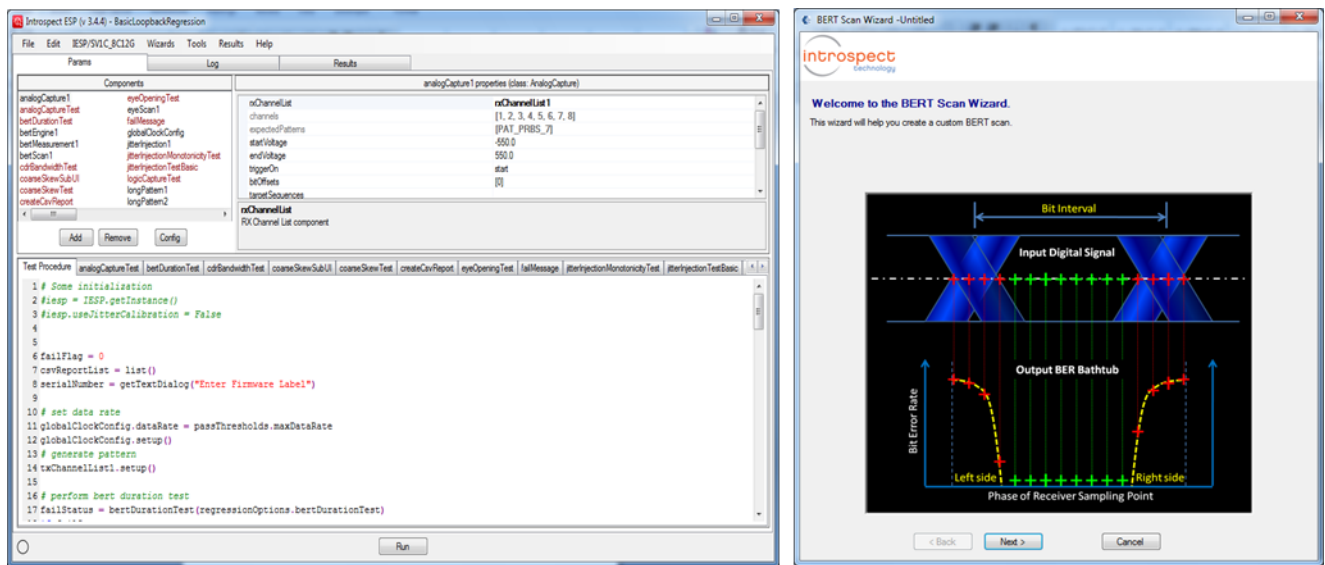


Figure 10 Sampling of analysis and report windows.

## Automation

The SV1C is operated using the award winning IntrospectESP Software. It features a comprehensive scripting language with an intuitive component-based design as shown in the screen shot in Figure 11(a). Component-based design is IntrospectESP's way of organizing the flexibility of the instrument in a manner that allows for easy program development. It highlights to the user only the parameters that are needed for any given task, thus allowing program execution in a matter of minutes. For further help, the SV1C features automatic code generation for common tasks such as Eye Diagram or Bathtub Curve generation as shown in Figure 11(b).



(a)

(b)

Figure 11 Screen capture of IntrospectESP user environment.

# Specifications

*Table 1 General Specifications*

Parameter	Value	Units	Description and Conditions
<b>Ports</b>			
Number of Differential Transmitters	8		Individually synthesized frequency and output format. Used as external Reference Clock input. Consult user manual for included capability. Contact factory for customization.
Number of Differential Receivers	8		
Number of Dedicated Clock Outputs	2		
Number of Dedicated Clock Inputs	1		
Number of Trigger Input Pins	Multiple		
Number of Flag Output Pins	Multiple		
<b>Data Rates and Frequencies</b>			
Minimum Programmable Data Rate	312.5	Mbps	Contact factory for extension to lower data rates.
Maximum Programmable Data Rate	14	Gbps	
Maximum Data Rate Purchase Options	4	Gbps	
	8.5	Gbps	
	12.5	Gbps	
	14	Gbps	
Data Rate Field Upgrade	4-12.5	Gbps	Contact factory for details.
Frequency Resolution of Programmed Data Rate	1	kHz	Finer resolution is possible. Contact factory for customization.
Minimum External Input Clock Frequency	25	MHz	
Maximum External Input Clock Frequency	250	MHz	
Supported External Input Clock I/O Standards			LVDS (typical 400 mVpp input) LVPECL (typical 800 mVpp input)
Minimum Output Clock Frequency	10	MHz	
Maximum Output Clock Frequency	250	MHz	
Output Clock Frequency Resolution	1	kHz	
Supported External Input Clock I/O Standards			Support for LVDS, LVPECL, CML, HCSL, and CMOS.

Table 2 Transmitter Characteristics

Parameter	Value	Units	Description and Conditions
<b>Output Coupling</b>			
DC common mode voltage	750	mV	typical (different offsets are firmware programmable)
AC Output Differential Impedance	100	Ohm	typical
<b>Voltage Performance</b>			
Minimum Differential Voltage Swing	20	mV	312.5 Mbps to 5 Gbps, 50 ohm AC coupled termination. 5 Gbps to 12.5 Gbps, 50 ohm AC coupled termination.
Maximum Differential Voltage Swing	1000 800	mVpp mVpp	
Differential Voltage Swing Resolution	20	mV	larger of: +/-10% of programmed value, and +/- 10mV
Accuracy of Differential Voltage Swing		%, mV	
Rise and Fall Time	50	ps	Typical, 500 mVpp signal, 20-80%, 50 ohm AC coupled termination.
	75	ps	Typical, 500 mVpp signal, 10%-90%, 50 ohm AC coupled termination.
<b>Pre-emphasis Performance</b>			
Pre-Emphasis Pre-Tap Range	-4 to +4	dB	Both high-pass and low-pass functions are available. This is the smallest achievable range based on worst-case conditions. Typical operating conditions result in wider pre-emphasis range.
Pre-Emphasis Pre-Tap Resolution	Range / 32	dB	Only high-pass function is available. This is the smallest achievable range based on worst-case conditions. Typical operating conditions result in wider pre-emphasis range.
Pre-Emphasis Post1-Tap Range	0 to 6	dB	
Pre-Emphasis Post1-Tap Resolution	Range / 32	dB	Both high-pass and low-pass functions are available. This is the smallest achievable range based on worst-case conditions. Typical operating conditions result in wider pre-emphasis range.
Pre-Emphasis Post2-Tap Range	-4 to +4	dB	
Pre-Emphasis Post2-Tap Resolution	Range / 32	dB	
<b>Jitter Performance</b>			
Random Jitter Noise Floor	700	fs	Based on measurement with high-bandwidth scope and with first-order clock recovery.
Minimum Frequency of Injected Deterministic Jitter	0.1	kHz	Contact factory for further customization.
Maximum Frequency of Injected Deterministic Jitter	80	MHz	
Frequency Resolution of Injected Deterministic Jitter	0.1	kHz	Contact factory for further customization.
Maximum Peak-to-Peak Injected Deterministic Jitter	1400	ps	This specification is separate from low-frequency wander generator and SSC generator.
Magnitude Resolution of Injected Deterministic Jitter	500	fs	Jitter injection is based on multi-resolution synthesizer, so this number is an effective resolution. Internal synthesizer resolution is defined in equivalent number of bits.
Injected Deterministic Jitter Setting	Per-bank		Common across all channels within a bank.
Maximum RMS Random Jitter Injection	0.1	UI	

Magnitude Resolution of Injected Jitter	0.1	ps	Common across all channels within a bank.
Accuracy of Injected Jitter Magnitude	larger of: +/-10% of programmed value, and +/-10 ps	%, ps	
Injected Random Jitter Setting	Common		
<b>Transmitter-to-Transmitter Skew Performance</b>			
Lane to Lane Integer-UI Minimum Skew	-20	UI	
Lane to Lane Integer-UI Maximum Skew	20	UI	
Effect of Skew Adjustment on Jitter Injection	None		
Lane to Lane Skew	+/- 30	ps	

Table 3 Receiver Characteristics

Parameter	Value	Units	Description and Conditions
<b>Input Coupling</b>			
AC Input Differential Impedance	100	Ohm	
<b>AC Performance</b>			
Minimum Detectable Differential Voltage	25	mV	
Maximum Allowable Differential Voltage	2000	mV	
Minimum Programmable Comparator Threshold Voltage	-550	mV	
Maximum Programmable Comparator Threshold Voltage	+550	mV	
Differential Comparator Threshold Voltage Resolution	10	mV	
Differential Comparator Threshold Voltage Accuracy	larger of: +/-10% of programmed value, and +/-10mV	%, mV	
Measured Eye Width Accuracy	10%		Maximum error, 312.5 Mbps – 2.0 Gbps, 200 mVpp minimum input amplitude Maximum error, 2.0 Mbps - 5 Gbps, 200 mVpp minimum input amplitude Maximum error, 5 Gbps – 12.5 Gbps, 200 mVpp minimum input amplitude
	15%		
	25%		
<b>Resolution Enhancement &amp; Equalization</b>			
DC Gain	0	dB	
	2	dB	
	4	dB	
	6	dB	
	8	dB	
	16	dB	
CTLE Maximum Gain	16	dB	
CTLE Resolution	1	dB	
DC Gain Control	Per-receiver		
Equalization Control	Per-receiver		

<b>Jitter Performance</b>			
Input Jitter Noise Floor in System Reference Mode	25	ps	
Input Jitter Noise Floor in Extracted Clock Mode	10	ps	
<b>Timing Generator Performance</b>			
Resolution at Maximum Data Rate	31.25	mUI	Resolution (as a percentage of UI) improves for lower data rate. Contact factory for details.
Differential Non-Linearity Error	+/- 0.5	LSB	
Integral Non-Linearity Error Range	+/- 5 Unlimited	ps	
<b>Skew</b>			
Lane to Lane Skew Measurement Accuracy	+/- 10	ps	

Table 4 Clocking Characteristics

Parameter	Value	Units	Description and Conditions
<b>Internal Time Base</b>			
Number of Internal Frequency References	2		Relevant for future customization.
<b>Embedded Clock Applications</b>			
Transmit Timing Modes	System Extracted		Clock can be extracted from one of the data receiver channels in order to drive all transmitter channels.
Receive Timing Modes	System Extracted		
Lane to Lane Tracking Bandwidth	4	MHz	All channels have clock recovery for extracted mode operation.
Single-Lane CDR Tracking Bandwidth	3 - 12	MHz	
<b>Forwarded Clock Applications</b>			
Transmit Timing Modes	System Forwarded		Channel 1 acts as forwarded clock for samplers.
Receive Timing Modes	System Forwarded		
Clock Tracking Bandwidth	4	MHz	Channel 1 acts as forwarded clock for samplers. Second order critically damped response.
<b>Spread Spectrum Support</b>			
Receive Lanes Track SSC Data	Yes		Requires operation in extracted clock mode. Consult factory for availability.
Transmit Lanes Generate SSC Data	Yes		
Minimum Spread	0.1	%	
Maximum Spread	2	%	
Spread Programming Resolution	0.01	%	
Minimum Spreading Frequency	31.5	kHz	
Maximum Spreading Frequency	63	kHz	



Table 5 Pattern Handling Characteristics

Parameter	Value	Units	Description and Conditions
<b>Loopback</b> Rx to Tx Loopback Capability Lane to Lane Latency Mismatch	Per channel 0	UI	
<b>Preset Patterns</b> Standard Built-In Patterns  Pattern Choice per Transmit Channel Pattern Choice per Receive Channel  BERT Comparison Mode	All Zeros D21.5 K28.5 K28.7 DIV.16 DIV.20 DIV.40 DIV.50 PRBS.5 PRBS.7 PRBS.9 PRBS.11 PRBS.13 PRBS.15 PRBS.21 PRBS.23 PRBS.31 Per-transmitter Per-receiver  Automatic seed generation for PRBS		Automatically aligns to PRBS data patterns.
<b>User Programmable Pattern Memory</b> Total Available Memory Individual Force Pattern Individual Expected Pattern Minimum Pattern Segment Size Maximum Pattern Segment Size Total Memory Space for Transmitters Total Expected Memory Space for Receivers	2 Per-transmitter Per-receiver 512 65536 1 1	GByte  bits bits Mbits Mbits	Memory allocation is customizable. Contact factory.  Memory allocation is customizable. Contact factory. Memory allocation is customizable. Contact factory.
<b>Pattern Sequencing</b> Sequence Control  Number of Sequencer Slots per Pattern Generator  Maximum Loop Count per Sequencer Slot	Loop infinite Loop on count Play to end 4  $2^{16} - 1$		This refers to the number of sequencer slots that can operate at any given time. The instrument has storage space for 16 different sequencer programs.
<b>Additional Pattern Characteristics</b> Pattern Switching  Raw Data Capture Length	Wait to end of segment Immediate 8192	  bits	When sourcing PRBS patterns, this option does not exist.

*Table 6 Measurement and Throughput Characteristics*

Parameter	Value	Units	Description and Conditions
<b>BERT Sync</b>			
Alignment Modes	Pattern PRBS		Module can align to any user pattern or preset pattern.
Minimum SYNC Error Threshold	3	bits	
Maximum SYNC Error Threshold	$2^{32}-1$	bits	
Minimum SYNC Sample Count	1024	bits	
Maximum SYNC Sample Count	$2^{32}$	bits	
SYNC Time	20	ms	Assumes a PRBS7 pattern that is stored in a user pattern segment and worst case misalignment between DUT pattern and expected pattern; data rate is 3.25 Gbps.
<b>BERT</b>			
Error Counter Size	32	bits	Sample counts in the BERT are programmed in increments of 32 bits.
Maximum Single-Shot Duration	$2^{32}-1$	bits	Repeat mode is available to continuously count over longer durations.
Continuous Duration	Indefinite		
<b>Alignment</b>			
CDR Lock Time	5	us	
Self-Alignment Time	50	ms	

*Table 7 Instruction Sequence Cache*

Parameter	Value	Units	Description and Conditions
<b>Simple Instruction Cache</b>			
Instruction Learn mode Instruction	Start Stop Replay		
<b>Advanced Instruction Cache</b>			
Local Instruction Storage	1M Instructions		
Instruction Sequence Segments	1000		

*Table 8 DUT Control Capabilities*

Parameter	Value	Units	Description and Conditions
<b>DUT IEEE-1149-1 (JTAG) Port (Option)</b>			
JTAG-Port Transmit Signals	TCK TRST TDI		
JTAG-Port Receive Signals	TDO		
JTAG-Port Transmit Voltage Swing (Fixed)	0 to 2.5	V	
JTAG-Port Receive Max Voltage Swing	0 to 2.5	V	
TDI Bit Memory	4k		
TDO Bit Memory	4k		
<b>DUT SPI Port (Option)</b>			
SPI Signals	SCLK SSN MISO MOSI		
Voltage Swing (Fixed)	0 to 2.5	V	

<b>Revision Number</b>	<b>History</b>	<b>Date</b>
<b>1.0</b>	Document release	Feb 27, 2013
<b>1.1</b>	Updated jitter injection specs, SSC specs, clock recovery specs; added block diagram descriptions	Oct 07, 2013
<b>1.2</b>	Minor edits	Oct 07, 2013
<b>1.3</b>	Update to specifications	Nov 12, 2013
<b>1.4</b>	Update to specifications	Apr 15, 2014
<b>1.5</b>	Update to specifications; removed test sequences	Aug 1, 2014
<b>1.6</b>	Updated document template	Jun 11, 2015
<b>1.7</b>	Added physical connectors info	Mar 11, 2016

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